

PERRY JOHNSON LABORATORY ACCREDITATION, INC.

Certificate of Accreditation

Perry Johnson Laboratory Accreditation, Inc. has assessed the Laboratory of:

Naval Systems Inc. 8551-1 Westside Industrial Dr., Jacksonville, FL 32219

(Hereinafter called the Organization) and hereby declares that Organization is accredited in accordance with the recognized International Standard:

ISO/IEC 17025:2005

This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (as outlined by the joint ISO-ILAC-IAF Communiqué dated January 2009):

Calibration of Dimensional, Electrical, Frequency, Mass, Force, Mechanical, and Thermodynamic Measuring Devices (As detailed in the supplement)

Accreditation claims for such testing and/or calibration services shall only be made from addresses referenced within this certificate. This Accreditation is granted subject to the system rules governing the Accreditation referred to above, and the Organization hereby covenants with the Accreditation body's duty to observe and comply with the said rules.

For PJLA:

Initial Accreditation Date:

Issue Date:

Accreditation No.:

Certificate No.:

February 14, 2009

February 26, 2013

60048

L13-38

Tracy Szerszen President/Operations Manager

Perry Johnson Laboratory Accreditation, Inc. (PJLA) 755 W. Big Beaver, Suite 1325 Troy, Michigan 48084

The validity of this certificate is maintained through ongoing assessments based on a continuous accreditation cycle. The validity of this certificate should be confirmed through the PJLA website www.pjlabs.com





Naval Systems Inc.

8551-1 Westside Industrial Dr., Jacksonville, FL 32219 David Rini Phone: 904-248-4325

Accreditation is granted to the facility to perform the following calibration:

Dimensional

MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Micrometer	25 mm to 330 mm	$(1.25 + 0.017L) \mu m$	Pratt & Whiney Lab Master Universal
	331 mm to 570 mm	(9.63 + 0.048L) μm	Gage Blocks ASME B89.1.9 Grade 0
Gage Blocks	0.5 mm to 100 mm	$(0.46 + 0.002L) \mu m$	Pratt & Whiney Lab Master
	101 mm to 305 mm	(0.21 + 0.006L) µm	Universal
Cylindrical Rings	10 mm to 330 mm	$(0.05 + 0.012L) \mu m$	
Cylindrical Plug and Discs	0.25 mm to 305 mm	$(0.35 + 0.012L) \mu m$	
Pin Gages	0.25 mm to 330 mm	$(0.35 + 0.012L) \mu m$	
Micrometer Standards	25 mm to 305 mm	$(0.33 + 0.005L) \mu m$	
	331 mm to 600 mm	6.35 μm	Fowler Z Cal 600 XT
Bore Gauges	6 mm to 300 mm	25 μm	Master Rings & Gauge Blocks
Calipers	25 mm to 305 mm	$(9.0 + 0.04L) \mu m$	Pratt & Whiney Lab Master Universal
	331 mm to 610 mm	21 µm	Fowler Z_Cal 600 XT
	610 mm to 2540 mm	127 μm	Gage Blocks ASME B89.1.9 Grade 0
Indicators	0.05 mm to 100 mm	3.0 µm	Pratt & Whiney LabMaster Universal
Height Gages	25 mm to 1 000 mm	$(5.3 + 0.026L) \mu m$	Gage Blocks ASME B89.1.9 Grade 0
Steel Rules	25 mm to 914 mm	397 μm	Gage Blocks ASME B89.1.9
Steel Tapes	25 mm to 3 650 mm	500 μm	Grade 2

MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Equipment to Measure	23 μV to 329.999 9 mV	$20 \mu V/V + 1 \mu V$	Fluke 5520A
DC Voltage	330 mV to 3.299 99 V	11 μV/V + 2 μV	
	3.3 V to 32.999 99 V	$12 \mu V/V + 20 \mu V$]
	30 V to 329.999 9 V	$18 \mu V/V + 150 \mu V$	
	100 V to 1 000.000 V	$18 \mu\text{V/V} + 1.5 \text{mV}$	



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Equipment to Output	0.3 μV to 200 mV	$5.0 \mu\text{V/V} + 0.1 \mu\text{V}$	Fluke 8508A
DC Voltage	200 mV to 2 V	$3.5 \mu\text{V/V} + 0.4 \mu\text{V}$	
	2 V to 20 V	$3.5 \mu\text{V/V} + 4.0 \mu\text{V}$]
	20 V to 200 V	$5.5 \mu\text{V/V} + 40.0 \mu\text{V}$	
	200 V to 1 000 V	$5.5 \mu\text{V/V} + 500 \mu\text{V}$	
Equipment to Measure	0.06 μA to 329.999 9 μA	$0.15 \text{ mA/A} + 0.02 \mu\text{A}$	Fluke 5520A
DC Current	330 μA to 3.299 99 mA	$0.10 \text{ mA/A} + 0.05 \mu\text{A}$	
	3.3 mA to 32.999 9 mA	$0.10 \text{ mA/A} + 0.25 \mu\text{A}$	1
	33 mA to 329.999 mA	$0.10 \text{ mA/A} + 2.5 \mu\text{A}$	1
	330 A 1.099 99 A	0.20 mA/A + 40 μA	-
	1.1 A to 2.999 99 A	$0.38 \text{ mA/A} + 40 \mu\text{A}$	-
	3 A to 10.999 9 A	$0.50 \text{ mA/A} + 500 \mu\text{A}$	1
	11 A to 20.5 A	1.0 mA/A + 750 μA	-
Equipment to Output	1.25 nA to 200 μA	$12 \mu\text{A/A} + 0.4 \text{nA}$	Fluke 8508A
DC Current	200 μA to 2 mA	$12 \mu A/A + 4 nA$	-
	2 mA to 20 mA	$14 \mu A/A + 40 nA$	5
	20 mA to 200 mA	48 μA/A + 8 μA	
	20 m A to2 A	185 μΑ/Α + 16 μΑ	
	2 A to 20 A	$0.4 \text{ mA/A} + 400 \mu\text{A}$	
Equipment to Measure AC At the listed frequencies	Voltage		Fluke 5520A
10 Hz to 45 Hz	1.0 mV to 32.999 mV	$0.80 \text{ mV/V} + 6 \mu\text{V}$	
45 Hz to 10 kHz	1.0 mV to 32.999 mV	$0.15 \text{ mV/V} + 6 \mu\text{V}$	
10 kHz to 20 kHz	1.0 mV to 32.999 mV	$0.20 \text{ mV/V} + 6 \mu\text{V}$	
20 kHz to 50 kHz	1.0 mV to 32.999 mV	$1.0 \text{ mV/V} + 6 \mu\text{V}$	1
50 kHz to 100 kHz	1.0 mV to 32.999 mV	$3.5 \text{ mV/V} + 12 \mu\text{V}$	1
100 kHz to 500 kHz	1.0 mV to 32.999 mV	$8.0 \text{ mV/V} + 50 \mu\text{V}$	1
Equipment to Measure AC At the listed frequencies	Voltage		-
10 Hz to 45 Hz	33 mV to 329.999 mV	$0.30 \text{ mV/V} + 8 \mu\text{V}$	1
45 Hz to 10 kHz	33 mV to 329.999 mV	$0.15 \text{ mV/V} + 8 \mu\text{V}$	
10 kHz to 20 kHz	33 mV to 329.999 mV	$0.16 \text{ mV/V} + 8 \mu\text{V}$	1
20 kHz to 50 kHz	33 mV to 329.999 mV	$0.35 \text{ mV/V} + 8 \mu\text{V}$	1
50 kHz to 100 kHz	33 mV to 329.999 mV	$0.80 \text{ mV/V} + 32 \mu\text{V}$	1
100 kHz to 500 kHz	33 mV to 329.999 mV	$2.0 \text{ mV/V} + 70 \mu\text{V}$	=
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Equipment to Measure AC	Voltage		Fluke 5520A
At the listed frequencies	0.22 X/ (2.200 00 X/	0.20 1/1/1 . 50 . 1/	_
10 Hz to 45 Hz	0.33 V to 3.299 99 V	$0.30 \text{ mV/V} + 50 \mu\text{V}$	_
45 Hz to 10 kHz	0.33 V to 3.299 99 V	$0.15 \text{ mV/V} + 60 \mu\text{V}$	
10 kHz to 20 kHz	0.33 V to 3.299 99 V	$0.19 \text{ mV/V} + 60 \mu\text{V}$	
20 kHz to 50 kHz	0.33 V to 3.299 99 V	$0.30 \text{ mV/V} + 50 \mu\text{V}$	
50 kHz to 100 kHz	0.33 V to 3.299 99 V	$0.70 \text{ mV/V} + 130 \mu\text{V}$	
100 kHz to 500 kHz	0.33 V to 3.299 99 V	$2.4 \text{ mV/V} + 600 \mu\text{V}$	
Equipment to Measure AC At the listed frequencies	Voltage		
10 Hz to 45 Hz	3.3 V to 32.999 9 V	$0.30 \text{ mV/V} + 650 \mu\text{V}$	
45 Hz to 10 kHz	3.3 V to 32.999 9 V	$1.50 \text{ mV/V} + 600 \mu\text{V}$	
10 kHz to 20 kHz	3.3 V to 32.999 9 V	$0.24 \text{ mV/V} + 600 \mu\text{V}$	
20 kHz to 50 kHz	3.3 V to 32.999 9 V	$0.35 \text{ mV/V} + 600 \mu\text{V}$	
50 kHz to 100 kHz	3.3 V to 32.999 9 V	0.90 mV/V + 1.6 mV	
Equipment to Measure AC At the listed frequencies	Voltage		
10 Hz to 45 Hz	33 V to 329.999 V	0.19 mV/V + 2.0 mV	
45 Hz to 10 kHz	33 V to 329.999 V	0.20 mV/V + 6.0 mV	
10 kHz to 20 kHz	33 V to 329.999 V	0.25 mV/V + 6.0 mV	
20 kHz to 50 kHz	33 V to 329.999 V	0.30 mV/V + 6.0 mV	
50 kHz to 100 kHz	33 V to 329.999 V	2.0 mV/V + 50.0 mV	
Equipment to Measure AC At the listed frequencies	Voltage		
45 Hz to 1 kHz	330 V to 1 020 V	0.30 mV/V + 10 mV	
1 kHz to 5 kHz	330 V to 1 020 V	0.25 mV/V + 10 mV	-
5 kHz to 10 kHz	330 V to 1 020 V	0.30 mV/V + 10 mV	-
Equipment to Output AC V At the listed frequencies	oltage		Fluke 8508A
1 Hz to 10 Hz	42.1 μV to 200 mV	$0.165 \text{ mV/V} + 14 \mu\text{V}$	
10 Hz to 40 Hz	12.0 μV to 200 mV	$0.140 \text{ mV/V} + 4 \mu\text{V}$	-
40 Hz to 100 Hz	12.0 µV to 200 mV	$0.115 \text{ mV/V} + 4 \mu\text{V}$	=
100 Hz to 2 kHz	6.0 µV to 200 mV	$0.110 \text{ mV/V} + 2 \mu\text{V}$	=
2 kHz to 10 kHz	12.0 µV to 200 mV	$0.135 \text{ mV/V} + 4 \mu\text{V}$	-
10 kHz to 30 kHz	24.0µV to 200 mV	$0.340 \text{ mV/V} + 8 \mu\text{V}$	1
30 kHz to 100 kHz	60.0 μV to 200 mV	$0.765 \text{ mV/V} + 20 \mu\text{V}$	-





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Equipment to Output AC Vo	İtage		Fluke 5520A
At the listed frequencies 1 Hz to 10 Hz	200 mV to 2 V	$0.15 \text{ mV/V} + 120 \mu\text{V}$	
10 Hz to 40 Hz	200 mV to 2 V	$0.115 \text{ mV/V} + 20 \mu\text{V}$	
40 Hz to 100 Hz	200 mV to 2 V	$0.09 \text{ mV/V} + 20 \mu\text{V}$	
100 Hz to 2 kHz	200 mV to 2 V	$0.075 \text{ mV/V} + 20 \mu\text{V}$	
2 kHz to 10 kHz	200 mV to 2 V	$0.11 \text{ mV/V} + 20 \mu\text{V}$	
10 kHz to 30 kHz	200 mV to 2 V	$0.22 \text{ mV/V} + 40 \mu\text{V}$	
30 kHz to 100 kHz	200 mV to 2 V	$0.57 \text{ mV/V} + 200 \mu\text{V}$	
100 kHz to 300 kHz	200 mV to 2 V	3.0 mV/V + 2 mV	
300 kHz to 1 MHz	200 mV to 2 V	0.057 mV/V + 20 mV	
Equipment to Output AC Vo At the listed frequencies	ltage	0	
1 Hz to 10 Hz	2 V to 20 V	0.15 mV/V + 1.2 mV	
10 Hz to 40 Hz	2 V to 20 V	$0.115 \text{ mV/V} + 200 \mu\text{V}$	
40 Hz to 100 Hz	2 V to 20 V	$0.09 \text{ mV/V} + 200 \mu\text{V}$	
100 Hz to 2 kHz	2 V to 20 V	$0.075 \text{ mV/V} + 200 \mu\text{V}$	
2 kHz to 10 kHz	2 V to 20 V	$0.11 \text{ mV/V} + 200 \mu\text{V}$	
10 kHz to 30 kHz	2 V to 20 V	$0.22 \text{ mV/V} + 400 \mu\text{V}$	
30 kHz to 100 kHz	2 V to 20 V	0.57 mV/V + 2 mV	
Equipment to Output AC Vo At the listed frequencies	ltage		Fluke 8508A
100 kHz to 300 kHz	2 V to 20 V	3.0 mV/V + 20 mV	
300 kHz to 1 MHz	2 V to 20 V	20 mV/V + 200 mV	
Equipment to Output AC Vo At the listed frequencies	ltage		
1 Hz to 10 Hz	200 V to 1 000 V	0.15 mV/V + 70 mV	
10 Hz to 40 Hz	200 V to 1 000 V	0.12 mV/V + 20 mV	
40 Hz to 100 Hz	200 V to 1 000 V	0.115 mV/V + 20 mV	
10 kHz to 30 kHz	200 V to 1 000 V	0.225 mV/V + 40 mV	
30 kHz to 100 kHz	200 V to 1 000 V	0.58 mV/V + 200 mV	





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QUANTITY OR GAUGE	APPROPRIATE	AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	EQUIPMENT AND REFERENCE STANDARDS USED
Equipment to Measure AC	Current		Fluke 5520A
At the listed frequencies 10 Hz to 20 Hz	29 μA to 329.99 μA	2.0 mA/A + 0.1 µA	-
20 Hz to 45 Hz	29 μA to 329.99 μA	$1.5 \text{ mA/A} + 0.1 \mu\text{A}$	-
45 Hz to 1 kHz	29 μA to 329.99 μA	$1.3 \text{ mA/A} + 0.1 \mu\text{A}$ $1.25 \text{ mA/A} + 0.1 \mu\text{A}$	
1 kHz to 5 kHz	29 μA to 329.99 μA	$3.0 \text{ mA/A} + 0.15 \mu\text{A}$	-
5 kHz to 10 kHz	29 μA to 329.99 μA	$8.0 \text{ mA/A} + 0.13 \mu\text{A}$	
10 kHz to 30 kHz	29 μA to 329.99 μA	$16 \text{ mA/A} + 0.2 \mu\text{A}$	
		10 ΠΑ/Α + 0.4 μΑ	
Equipment to Measure AC At the listed frequencies	Current		
10 Hz to 20 Hz	0.33 mA to 3.299 9 mA	2.0 mA/A + 0.15 μA	
20 Hz to 45 Hz	0.33 mA to 3.299 9 mA	$1.25 \text{ mA/A} + 0.15 \mu\text{A}$	
45 Hz to 1 kHz	0.33 mA to 3.299 9 mA	$1.0 \text{ mA/A} + 0.15 \mu\text{A}$	
1 kHz to 5 kHz	0.33 mA to 3.299 9 mA	$2.0 \text{ mA/A} + 0.2 \mu\text{A}$	
5 kHz to 10 kHz	0.33 mA to 3.299 9 mA	$5.0 \text{ mA/A} + 0.3 \mu\text{A}$	
10 kHz to 30 kHz	0.33 mA to 3.299 9 mA	$10 \text{ mA/A} + 0.6 \mu\text{A}$	
Equipment to Measure AC At the listed frequencies	Current	10	
10 Hz to 20 Hz	3.3 mA to 32.999 mA	$1.8 \text{ mA/A} + 2 \mu\text{A}$	
20 Hz to 45 Hz	3.3 mA to 32.999 mA	$0.9 \text{ mA/A} + 2 \mu\text{A}$	
45 Hz to 1 kHz	3.3 mA to 32.999 mA	$0.4 \text{ mA/A} + 2 \mu \text{A}$	
1 kHz to 5 kHz	3.3 mA to 32.999 mA	$0.8 \text{ mA/A} + 2 \mu\text{A}$	
5 kHz to 10 kHz	3.3 mA to 32.999 mA	$2.0 \text{ mA/A} + 3 \mu\text{A}$	
10 kHz to 30 kHz	3.3 mA to 32.999 mA	$4.0 \text{ mA/A} + 4 \mu\text{A}$	
Equipment to Measure AC At the listed frequencies	Current		
10 Hz to 20 Hz	33 mA to 329.99 mA	$1.8 \text{ mA/A} + 20 \mu\text{A}$	
20 Hz to 45 Hz	33 mA to 329.99 mA	$0.9 \text{ mA/A} + 20 \mu\text{A}$	
45 Hz to 1 kHz	33 mA to 329.99 mA	$0.4 \text{ mA/A} + 20 \mu\text{A}$	
1 kHz to 5 kHz	33 mA to 329.99 mA	$1.0 \text{ mA/A} + 50 \mu\text{A}$	1
5 kHz to 10 kHz	33 mA to 329.99 mA	$2.0 \text{ mA/A} + 100 \mu\text{A}$	
10 kHz to 30 kHz	33 mA to 329.99 mA	$4.0 \text{ mA/A} + 200 \mu\text{A}$	





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Equipment to Measure AC C	Fluke 5520A		
At the listed frequencies 10 Hz to 45 Hz	0.33 A to 1.099 99 A	1.8 mA/A + 100 μA	
45 Hz to 1 kHz	0.33 A to 1.099 99 A	$0.5 \text{ mA/A} + 100 \mu\text{A}$	
1 kHz to 5 kHz	0.33 A to 1.099 99 A	6.0 mA/A + 1.0 mA	
5 kHz to 10 kHz	0.33 A to 1.099 99 A	25 mA/A + 5.0 mA	
Equipment to Measure AC C At the listed frequencies	urrent		
10 Hz to 45 Hz	1.1 A to 2.999 99 A	1.8 mA/A + 100 μA	
45 Hz to 1 kHz	1.1 A to 2.999 99 A	0.6 mA/A + 100 μA	
1 kHz to 5 kHz	1.1 A to 2.999 99 A	6.0 mA/A + 1.0 mA	
5 kHz to 10 kHz	1.1 A to 2.999 99 A	25 mA/A + 5.0 mA	
Equipment to Measure AC C At the listed frequencies			
45 Hz to 100 Hz	3 A to 10.999 99A	0.6 mA/A + 2.0 mA	
100 Hz to 1 kHz	3 A to 10.999 99A	1.0 mA/A + 2.0 mA	
1 kHz to 5 kHz	3 A to 10.999 99A	30 mA/A + 2.0 mA	
Equipment to Measure AC C At the listed frequencies		4-0	
45 Hz to 100 Hz	11 A to 20.5 A	1.2 mA/A + 5.0 mA	
100 Hz to 1 kHz	11 A to 20.5 A	1.5 mA/A + 5.0 mA	
1 kHz to 5 kHz	11 A to 20.5 A	31 mA/A + 5.0 mA	
Equipment to Output AC Cu: At the listed frequencies			Fluke 8508A
1 Hz to 10 Hz	12 μA to 200 μA	$0.5 \text{ mA/A} + 0.02 \mu\text{A}$	
10 Hz to 10 kHz	12 μA to 200 μA	$0.5 \text{ mA/A} + 0.02 \mu\text{A}$	
10 kHz to 30 kHz	12 μA to 200 μA	$0.71 \text{ mA/A} + 0.02 \mu\text{A}$	
30 kHz to 100 kHz	12 μA to 200 μA	$4.0 \text{ mA/A} + 0.02 \mu\text{A}$	
Equipment to Output AC Cu: At the listed frequencies	rrent		
1 Hz to 10 Hz	200 μA to 2 mA	0.31 mA/A + 0.2 μ A	
10 Hz to 10 kHz	200 μA to 2 mA	$0.30 \text{ mA/A} + 0.2 \mu\text{A}$	
10 kHz to 30 kHz	200 μA to 2 mA	$0.71 \text{ mA/A} + 0.2 \mu\text{A}$	
30 kHz to 100 kHz	200 μA to 2 mA	$4.0 \text{ mA/A} + 0.2 \mu\text{A}$	





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Equipment to Output AC Cu	rrent		Fluke 8508A
At the listed frequencies			
1 Hz to 10 Hz	2 mA to 20 mA	$0.31 \text{mA/A} + 2 \mu \text{A}$	
10 Hz to 10 kHz	2 mA to 20 mA	$0.30 \text{ mA/A} + 2 \mu\text{A}$	
10 kHz to 30 kHz	2 mA to 20 mA	$0.71 \text{ mA/A} + 2 \mu\text{A}$	
30 kHz to 100 kHz	2 mA to 20 mA	$4.0 \text{ mA/A} + 2 \mu\text{A}$	
Equipment to Output AC Cu At the listed frequencies			
1 Hz to 10 Hz	20 mA to 200 mA	$0.31 \text{ mA/A} + 20 \mu\text{A}$	
10 Hz to 10 kHz	20 mA to 200 mA	$0.29 \text{ mA/A} + 20 \mu\text{A}$	
10 kHz to 30 kHz	20 mA to 200 mA	$0.625 \text{ mA/A} + 20 \mu\text{A}$	
Equipment to Output AC Cu At the listed frequencies			
10 Hz to 2 kHz	200 mA to 2 A	0.62 mA/A + 0.20 mA	
2 kHz to 10 kHz	200 mA to 2 A	0.735 mA/A + 0.20 mA	
10 kHz to 30 kHz	200 mA to 2 A	3.0 mA/A + 0.20 mA	
Equipment to Output AC Cu At the listed frequencies	rrent	N R	
10 Hz to 2 kHz	2 A to 20 A	0.82 mA/A + 2 mA	
2 kHz to 10 kHz	2 A to 20 A	2.5 mA/A + 2 mA	
Equipment to Measure	3 mΩ to 10.999 9 Ω	40 μΩ/Ω + 1 mΩ	Fluke 5520A
Resistance	11 Ω to 32.999 9 Ω	$30 \mu\Omega/\Omega + 1.5 \mathrm{m}\Omega$	
	33 Ω to 109.999 9 Ω	28 μΩ/Ω + 1.4 mΩ	
	110 Ω to 329.999 9 Ω	$28 \mu\Omega/\Omega + 2 \mathrm{m}\Omega$	
	330 Ω to 1.099 999 kΩ	$28 \mu\Omega/\Omega + 2 \mathrm{m}\Omega$	
	1.1 kΩ to 3.2999 999 kΩ	$28 \mu\Omega/\Omega + 20 \mathrm{m}\Omega$	
	3.3 kΩ to 10.999 99 kΩ	$28 \mu\Omega/\Omega + 20 \mathrm{m}\Omega$	
	11 kΩ to 32.999 99 kΩ	$28 \mu\Omega/\Omega + 0.2 \Omega$	
	33 kΩ to 109.999 9 kΩ	$28 \mu\Omega/\Omega + 0.2 \Omega$	
	110 kΩ to 329.999 9 kΩ	$32 \mu\Omega/\Omega + 2 \Omega$	
	330 kΩ to 1.099 99 kΩ	$32 \mu\Omega/\Omega + 2 \Omega$	
	1.1 MΩ to 3.299 999 MΩ	60 μΩ/Ω + 30 Ω	
	3.3 MΩ to 10.999 99 MΩ	$0.13 \text{ m}\Omega/\Omega + 50 \Omega$	
	11 MΩ to 32.999 99 MΩ	$0.25 \text{ m}\Omega/\Omega + 2.5 \text{ k}\Omega$	





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Equipment to Measure	33 MΩ to 109.999 9 MΩ	$0.50 \text{ m}\Omega/\Omega + 3 \text{ k}\Omega$	Fluke 5520A
Resistance	110 MΩ to 329.999 9 MΩ	$3 \text{ m}\Omega/\Omega + 100 \text{ k}\Omega$	
	$330~\mathrm{M}\Omega$ to $1~110~\mathrm{M}\Omega$	$15 \text{ m}\Omega/\Omega + 500 \text{ k}\Omega$	
Equipment to Output	12 μΩ to 2 Ω	17 μ Ω / Ω + 4.0 μ Ω	Fluke 8508A -
Resistance	2 Ω to 20 Ω	$9.5 \mu\Omega/\Omega + 14 \mu\Omega$	Normal
	20Ω to $2 k\Omega$	$8 \mu\Omega/\Omega + 0.5 m\Omega$	
	$2 \text{ k}\Omega \text{ to } 20 \text{ k}\Omega$	$8 \mu\Omega/\Omega + 5.0 m\Omega$	
	20 kΩ to 200 kΩ	$8 \mu\Omega/\Omega + 50 m\Omega$	
	200 kΩ to 2 M Ω	9 μ Ω / Ω + 1.0 Ω	
	$2 \text{ M} \Omega \text{ to } 20 \text{ M}\Omega$	$20 \mu\Omega/\Omega + 100 \Omega$	
	20 MΩ to 200 MΩ	$120 \mu\Omega/\Omega + 10 k\Omega$	
	$200~\mathrm{M}\Omega$ to $2~\mathrm{G}\Omega$	$1.51 \text{ m}\Omega/\Omega + 1 \text{ M}\Omega$	
Equipment to Measure	0.19 nF to 0.399 9 nF	5 mF/F + 0.01 nF	Fluke 5520A
Capacitance At the listed frequencies 10 Hz to 10 kHz	0.4 nF to 1.099 9 nF	5 mF/F + 0.01 nF	
Equipment to Measure Capacitance At the listed frequencies 10 Hz to 3 kHz	0.1.1 nF to 3.299 9 nF	5 mF/F + 0.01 nF	
Equipment to Measure	3.3 nF to 10.999 9 nF	2.5 mF/F + 0.01 nF	
Capacitance	11 nF to 32.999 9 nF	2.5 mF/F + 0.1 nF	
At the listed frequencies 10 Hz to 1kHz	33 nF to 109.999 nF	2.5 mF/F + 0.1 nF	
	110 nF to 329.999 nF	2.5 mF/F + 0.3 nF	
Equipment to Measure Capacitance At the listed frequencies 10 Hz to 600 Hz	0.33 μF to 1.099 99 μF	2.5 mF/F + 1 nF	
Equipment to Measure Capacitance At the listed frequencies 10 Hz to 300 Hz	1.1 μF to 3.29 999 μF	2.5 mF/F + 3 nF	
Equipment to Measure Capacitance At the listed frequencies 10 Hz to 150 Hz	3.3 μF to 10.999 9 μF	2.5 mF/F + 10 nF	





Naval Systems Inc.

8551-1 Westside Industrial Dr., Jacksonville, FL 32219 David Rini Phone: 904-248-4325

Accreditation is granted to the facility to perform the following calibration:

MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Equipment to Measure Capacitance At the listed frequencies 10 Hz to 120 Hz	11 μF to 32.999 9 μF	4 mF/F + 30 nF	Fluke 5520A
Equipment to Measure Capacitance At the listed frequencies 10 Hz to 80 Hz	33 μF to 109.999 μF	4.5 mF/F + 100 nF	
Equipment to Measure Capacitance At the listed frequencies 0 Hz to 50 Hz	110 μF to 329.999 μF	4.5 mF/F + 300 nF	
Equipment to Measure Capacitance At the listed frequencies 0 Hz to 20 Hz	0.33 mF to 1.099 99 mF	4.5 mF/F + 1 μF	
Equipment to Measure Capacitance At the listed frequencies 0 Hz to 6 Hz	1.1 mF to 3.299 9 mF	4.5 mF/F + 3 μF	
Equipment to Measure Capacitance At the listed frequencies 0 Hz to 2 Hz	3.3 mF to 10.999 9 mF	4.5 mF/F + 10 μF	
Equipment to Measure Capacitance At the listed frequencies 0 Hz to 0.6 Hz	11 mF to 32.999 9 mF	7.5 mF/F + 30 μF	
Equipment to Measure Capacitance At the listed frequencies 0 Hz to 0.2 Hz	33 mF to 110 mF	11 mF/F + 100 μF	
Equipment to Measure	100 mW to 250 mW	11.5 mW/W	Fluke 9640A
Power At the listed frequencies	25 mW to 100 mW	11.5 mW/W	
10 Hz to 20 kHz	20 μW to 25 mW	11.6 mW/W	
	16 nW to 20 μW	11.6 mW/W	
Equipment to Measure	100 mW to 250 mW	11.5 mW/W	
Power At the listed frequencies	25 mW to 100 mW	11.5 mW/W	
20 kHz to 100 kHz	20 μW to 25 mW	11.6 mW/W	
	16 nW to 20 μW	11.6 mW/W	





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Equipment to Measure	100 mW to 250 mW	11.5 mW/W	Fluke 9640A
Power At the listed frequencies	25 mW to 100 mW	11.5 mW/W	
100 kHz to 10 MHz	20 uW to 25 mW	11.6 mW/W	
	16 nW to 20 uW	11.6 mW/W	
	40 pW to 16 nW	47.1 mW/W	
	4 pW to 40 pW	122.0 mW/W	
	0.4 pW to 4 pW	122.0mW/W	
Equipment to Measure	100 mW to 250 mW	11.5 mW/W	_
Power At the listed frequencies	25 mW to 100 mW	11.5 mW/W	-
10 MHz to 125 MHz	20 μW to 25 mW	11.6 mW/W	-
	16 nW to 20 μW	11.6 mW/W	
	40 pW to 16 nW	47.1 mW/W	
Equipment to Measure	4 pW to 40 pW	122.0 mW/W	1
Power	0.4 pW to 4 pW	122.0 mW/W	_
At the listed frequencies 10 MHz to 125 MHz	1 fW to 0.4 pW	412.5 mW/W	
Equipment to Measure	100 mW to 250 mW	11.5 mW/W	
Power At the listed frequencies	25 mW to 100 m	11.5 mW/W	
10 MHz to 125 MHz	20 μW to 25 mW	11.6 mW/W	
	16 nW to 20 μW	11.6 mW/W	
	40 pW to 16 nW	47.1 mW/W	
	4 pW to 40 pW	122.0 mW/W	
	0.4 pW to 4 pW	122.0 mW/W	
	1 fW to 0.4 pW	412.5 mW/W	-
Equipment to Measure	25 mW to 100 mW	23.3 mW/W	-
Power	20 μW to 25 mW	23.3 mW/W	-
At the listed frequencies 125 MHz to 300 MHz	16 nW to 20 uW	23.3 mW/W	1
	40 pW to 16 nW	47.1 mW/W	1
	4 pW to 40 pW	122.0 mW/W	1
	0.4 pW to 4 pW	122.0 mW/W	1
	1 fW to 0.4 pW	412.5 mW/W	1





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MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Equipment to Measure Power At the listed frequencies 300 MHz to 1.4 GHz	25 mW to 100 mW	59.3 mW/W	Fluke 9640A
	20 μW to 25 mW	59.3 mW/W	
300 MHZ to 1.4 GHZ	16 nW to 20 μW	122.0 mW/W	
	40 pW to 16 nW	122.0 mW/W	
	4 pW to 40 pW	258.9 mW/W	
	0.4 pW to 4 pW	258.9 mW/W	
	1 fW to 0.4 pW	412.5 mW/W	
Equipment to Measure Power	20 μW to 25 mW	71.5 mW/W	
At the listed frequencies 1.4 GHz to 3 GHz	16 nW to 20 μW	122.0 mW/W]
1.4 GHZ to 3 GHZ	4 pW to 40 pW	258.9 mW/W	
	0.4 pW to 4 pW	258.9 mW/W]
	1 fW to 0.4 pW	412.5 mW/W]
Equipment to Measure Power	20 μW to 25 mW	122.0 mW/W	
At the listed frequencies 3 GHz to 4 GHz	16 nW to 20 μW	122.0 mW/W	
3 GHZ to 4 GHZ	40 pW to 16 nW	122.0 mW/W	
	4 pW to 40 pW	258.9 mW/W	
Equipment to Output Power At the listed frequencies 9 kHz to 6 GHz	1 nW to 100 mW	3 % of reading	Agilent U2004A
Equipment to Output Power At the listed frequencies 100 kHz to 2.6 GHz	10 μW to 1.0 W	122.0 mW/W	Hewlett Packard 8901B with 11722A
Temperature Calibration,	600 °C to 800 °C	0.44 °C	Electrical Simulation
Indication and Control Equipment used with	800 °C to 1 000 °C	0.34 °C	of Thermocouple Output
Thermocouple Type B	1 000 °C to 1 550 °C	0.30 °C	Fluke 5520A
The Incompleting the B	1 550 °C to 1 820 °C	0.33 °C	
Temperature Calibration,	0 °C to 150 °C	0.30 °C	
Indication and Control Equipment used with	150 °C to 650 °C	0.26 °C	
Thermocouple Type C	650 °C to 1 000 °C	0.31 °C	-
r . Jr	1 000 °C to 1 800 °C	0.50 °C	
	1 800 °C to 2 316 °C	0.84 °C	





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MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Temperature Calibration, Indication and Control Equipment used with Thermocouple Type E	-250 °C to -100 °C	0.50 °C	Electrical Simulation of Thermocouple Output Fluke 5520A
	-100 °C to -25 °C	0.16 °C	
	-25 °C to 350 °C	0.14 °C	
	350 °C to 650 °C	0.17 °C	
	650 °C to 1 000 °C	0.24 °C	
Temperature Calibration,	-210 °C to -100 °C	0.27 °C	
Indication and Control Equipment used with	-100 °C to -25 °C	0.16 °C	
Thermocouple Type J	-30 °C to 150 °C	0.14 °C	
	150 °C to 760 °C	0.18 °C	
	760 °C to 1 200 °C	0.24 °C	
Temperature Calibration,	-200 °C to -100 °C	0.33 °C	
Indication and Control	-100 °C to -25 °C	0.18 °C	
Equipment used with Thermocouple Type K	-25 °C to 120 °C	0.16 °C	
J1	120 °C to 1 000 °C	0.26 °C	
	1 000 °C to 1 372 °C	0.40 °C	
Temperature Calibration,	-200 °C to -100 °C	0.40 °C	
Indication and Control Equipment used with	-100 °C to -25 °C	0.22 °C	
Thermocouple Type N	-125 °C to 120 °C	0.19 °C	
J1	120 °C to 410 °C	0.18 °C	
	410 °C to 1 300 °C	0.27 °C	
Temperature Calibration,	0 °C to 250 °C	0.57 °C	
Indication and Control	250 °C to 400 °C	0.35 °C	
Equipment used with Thermocouple Type R	400 °C to 1 000 °C	0.33 °C]
	1 000 °C to 1 767 °C	0.40 °C	
Temperature Calibration, Indication and Control Equipment used with Thermocouple Type T	-250 °C to -15 °C	0.63 °C	
	-150 °C to 0 °C	0.24 °C	
	0 °C to 120 °C	0.16 °C	
	120 °C to 400 °C	0.14 °C	





Naval Systems Inc.

8551-1 Westside Industrial Dr., Jacksonville, FL 32219 David Rini Phone: 904-248-4325

Accreditation is granted to the facility to perform the following calibration:

Mass, Force, and Weighing Devices

MEASURED INSTRUMENT, QUANTITY OR GAUGE Mass ANSI/ASTM Class 7	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE 0.05 g to 61 g 61 g to 4 100 g	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±) 0.000 5 g 0.05 g	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED Denver TL-64 Ohaus E1D120
	4.1 kg to 15 kg	0.49 g	Fairbanks 70-6115
Force-Tension & Compression, Forces Gages	2 N to 445 N	0.4 N	Omega LC101-100 with DPM-3
and Load Cell Based Devices	445 N to 2 225 N	1.35 N	Omega LC101-500 with DPM-3
	2 225 N to 9 000 N	4.9 N	Omega LC101-2K with DPM-3
	9 000 N to 45 000 N	22 N	Omega LC101-10K with DPM-3
	45 000 N to 177 000 N	279 N	Omega LC101-40K with DPM-3
Force- Compression	44 500 N to 450 000 N	268 N	OmegaDyne LC1102-100K with Transducer Techniques DPM-3

Mechanical

Micchanicai			
MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Torque Wrenches	45.2 N•cm to 226 N•cm	0.59 % of Reading	Mountz S 320
	3.40 N•m to 16.9 N•m	0.77 % of Reading	AWS 3015
	3.00 N•m to 28.25 N•m	0.73 % of Reading	CDI 2502-I-DDT
	34.0 N•m to 340 N•m	0.65 % of Reading	Armstrong 64-646
	160 N•m to 813 N•m	1.0 % of Reading	Snap On TQTP 600
	150 N•m to 1 500 N•m	4.1 N•m	Transducer Techniques SWS-1k with Transducer Techniques DPM-3
Torque Analyzers	6.77 N•m to 339 N•m	0.065 % of Applied Load	TTP250with Class F weights
Equipment to Measure Pressure	5 kPa to 7 MPa (abs)	$(10 + 3.7 \times 10^{-5} P) Pa$	DHI PG7601
	160 kPa to 52 000 kPa (rel. to atm)	52 kPa	Ashcroft ATE-100/AQS-2
	52 000 kPa to 280 000 kPa (rel. to atm)	$(62 + 5.7 \times 10^{-3} \text{ P}) \text{ kPa}$	Ruska 2451 625-M100





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Accreditation is granted to the facility to perform the following calibration:

Thermodynamic

MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE (AND SPECIFICATION WHERE APPROPRIATE)	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Equipment to Measure	-45 °C to 140 °C	0.034 °C	Hart Scientific 9170, Hart
Temperature			Scientific 5616-12, and Fluke
Thermistors			8508A
RTDs	-45 °C to 140 °C	0.10 °C	Hart Scientific 9170, Hart Scientific 5616-12, and Fluke 8508A
	141 °C to 320 °C	0.59 °C	King Nutronics Drywell 3604, Hart Scientific 5616-12, and Fluke 8508A
	321 °C to 650 °C	(0.11 + 0.001 5Te) °C	King Nutronics Drywell 3604-1-101
Thermocouples	-45 °C to 140 °C	0.18 °C	Hart Scientific 9170, Hart
•			Scientific 5616, and Fluke 8508A
	141 °C to 320 °C	0.61 °C	King Nutronics Drywell 3604, Hart Scientific 5616-12, and Fluke 8508A
	321 °C to 650 °C	(0.11 + 0.001 5Te) °C	King Nutronics Drywell 3604
Liquid in Glass Thermometers	-45 °C to 140 °C	0.31 °C	Hart Scientific 9170, Hart Scientific 5616, and Fluke 8508A
	141 °C to 320 °C	0.97 °C	King Nutronics Drywell 3604, Hart Scientific 5616-12, and Fluke 8508A
	321 °C to 650 °C	1.2 °C	King Nutronics Drywell 3604
IR Devices	50 °C to 121 °C	0.4 0.95 °C	Extech IRC350
	122 °C to 260 °C	1.34 °C	Hart Scientific 5616-12, and
	261 °C to 350 °C	2.03 °C	Fluke 8508A
Equipment to Source	-196 °C to 125 °C	0.18 °C	Hart Scientific 5616 with
Temperature	125 °C to 420 °C	0.28 °C	Fluke 8508A
Bath and Block Calibrators			





Naval Systems Inc.

8551-1 Westside Industrial Dr., Jacksonville, FL 32219 David Rini Phone: 904-248-4325

Accreditation is granted to the facility to perform the following calibration:

Time and Frequency

Time and Frequency			
MEASURED	RANGE OR NOMINAL DEVICE	CALIBRATION	CALIBRATION
INSTRUMENT,	SIZE AS APPROPRIATE	AND MEASUREMENT	EQUIPMENT AND
QUANTITY OR GAUGE		CAPABILITY EXPRESSED	REFERENCE
		AS AN UNCERTAINTY (±)	STANDARDS USED
Equipment to Measure	10 MHz	64 μHz	GPS Time Standard-
Frequency			Hewlett Packard Z3801A
	10 Hz to 4 GHz	160 μHz + 0.04 μHz/Hz	Fluke 9640A
	1 GHz to 20 GHz	3.7 µHz/Hz	Agilent 83731B-1E1 with
		·	Hewlett Packard Z3801A
Equipment to Output	10 Hz to 20 GHz	2 μHz/Hz	Hewlett Packard 5350B with
Frequency	Resolutions to 1 Hz		Hewlett Packard Z3801A

- 1. The CMC (Calibration and Measurement Capability) stated for calibrations included on this scope of accreditation represent the smallest measurement uncertainties attainable by the laboratory when performing a more or less routine calibration of a nearly ideal device under nearly ideal conditions. It is expressed at a confidence level of 95 % using a coverage factor k (usually equal to 2). The actual measurement uncertainty associated with a specific calibration performed by the laboratory will typically be larger than the CMC for the same calibration since capability and performance of the device being calibrated and the conditions related to the calibration may reasonably be expected to deviate from ideal to some degree.
- 2. The laboratories range of calibration capability for all disciplines for which they are accredited is the interval from the smallest calibrated standard to the largest calibrated standard used in performing the calibration. The low end of this range must be an attainable value for which the laboratory has or has access to the standard referenced. Verification of an indicated value of zero in the absence of a standard is common practice in the procedure for many calibrations but by its definition it does not constitute calibration of zero capacity.
- 3. When calibrations are performed at customer locations the resulting measurement uncertainty associated with the calibration will typically be larger than the CMC stated on this scope of accreditation. This is due in large part to variation of environmental conditions at customer facilities, the effects of transport on any standards or equipment taken to customer sites and the resolution and repeatability unique to the device being calibrated.
- 4. The term L represents length in inches or millimeters appropriate to the uncertainty statement.
- 5. The term P represents pressure in Pascals or kPascals appropriate to the uncertainty statement.
- 6. The term T represents torque in Newton•meters.
- 7. The term F represents force in Newtons.
- 8. The term Te represents temperature in °C.



Perry Johnson Laboratory Accreditation, Inc.



February 26, 2013

Mr. David Rini Naval Systems Inc. 8551-1 Westside Industrial Dr. Jacksonville, FL 32219

Dear Mr. Rini;

This letter is to confirm that you have successfully completed your reaccreditation assessment. A certificate has now been granted and posted on our website. As you are aware, PJLA will no longer be issuing expiration dates on our certificates. Your certificate # L13-38 will remain valid as long as you continue to maintain your annual assessments and reaccreditation assessments as stated in your customer agreement with PJLA. At this time, we have confirmed that your annual assessments will be conducted during the month of **February** each calendar year. This will include an interim surveillance assessment and a full system reassessment to be completed by **February 2015**. Once your reassessment is conducted and approved by our accreditation committee a revised status letter will be provided to you. Please allow PJLA at least 120 days from your assessment due date to issue this letter.

Please feel free to release this letter to any interested parties as confirmation of your certificate validity. Also, please remind them that your certificate is posted on our website at all times. Any changes in regards to your accreditation status will be reflected on our website.

We would like to thank you for your patronage over the past years and look forward to continuously serving your accreditation needs in the future. If we can assist you any further, please feel free to contact us at any time.

Sincerely,

Tracy Szerszen

President/Operations Manager